

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/755,659	CHEN ET AL.	
Examiner	Art Unit	
Christine Na	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
370	311	1/9/2008	CN	
370	335	1/9/2008	CN	
370	337	1/9/2008	CN	
370	342	1/9/2008	CN	
370	347	1/9/2008	CN	
455	69	1/9/2008	CN	
455	522	1/9/2008	CN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
Huy Vu		1/9/2008	CN	
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